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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	600
Number of Logic Elements/Cells	2700
Total RAM Bits	40960
Number of I/O	176
Number of Gates	100000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-BGA
Supplier Device Package	256-FBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc2s100-6fgg256c

Spartan-II Product Availability

Table 2 shows the maximum user I/Os available on the device and the number of user I/Os available for each device/package combination. The four global clock pins are usable as additional user I/Os when not used as a global clock pin. These pins are not included in user I/O counts.

Table 2: Spartan-II FPGA User I/O Chart⁽¹⁾

Device	Maximum User I/O	Available User I/O According to Package Type					
		VQ100 VQG100	TQ144 TQG144	CS144 CSG144	PQ208 PQG208	FG256 FGG256	FG456 FGG456
XC2S15	86	60	86	(Note 2)	-	-	-
XC2S30	92	60	92	92	(Note 2)	-	-
XC2S50	176	-	92	-	140	176	-
XC2S100	176	-	92	-	140	176	(Note 2)
XC2S150	260	-	-	-	140	176	260
XC2S200	284	-	-	-	140	176	284

Notes:

1. All user I/O counts do not include the four global clock/user input pins.
2. Discontinued by [PDN2004-01](#).

Boundary-scan operation is independent of individual IOB configurations, and unaffected by package type. All IOBs, including unbonded ones, are treated as independent 3-state bidirectional pins in a single scan chain. Retention of the bidirectional test capability after configuration facilitates the testing of external interconnections.

Table 7 lists the boundary-scan instructions supported in Spartan-II FPGAs. Internal signals can be captured during EXTEST by connecting them to unbonded or unused IOBs. They may also be connected to the unused outputs of IOBs defined as unidirectional input pins.

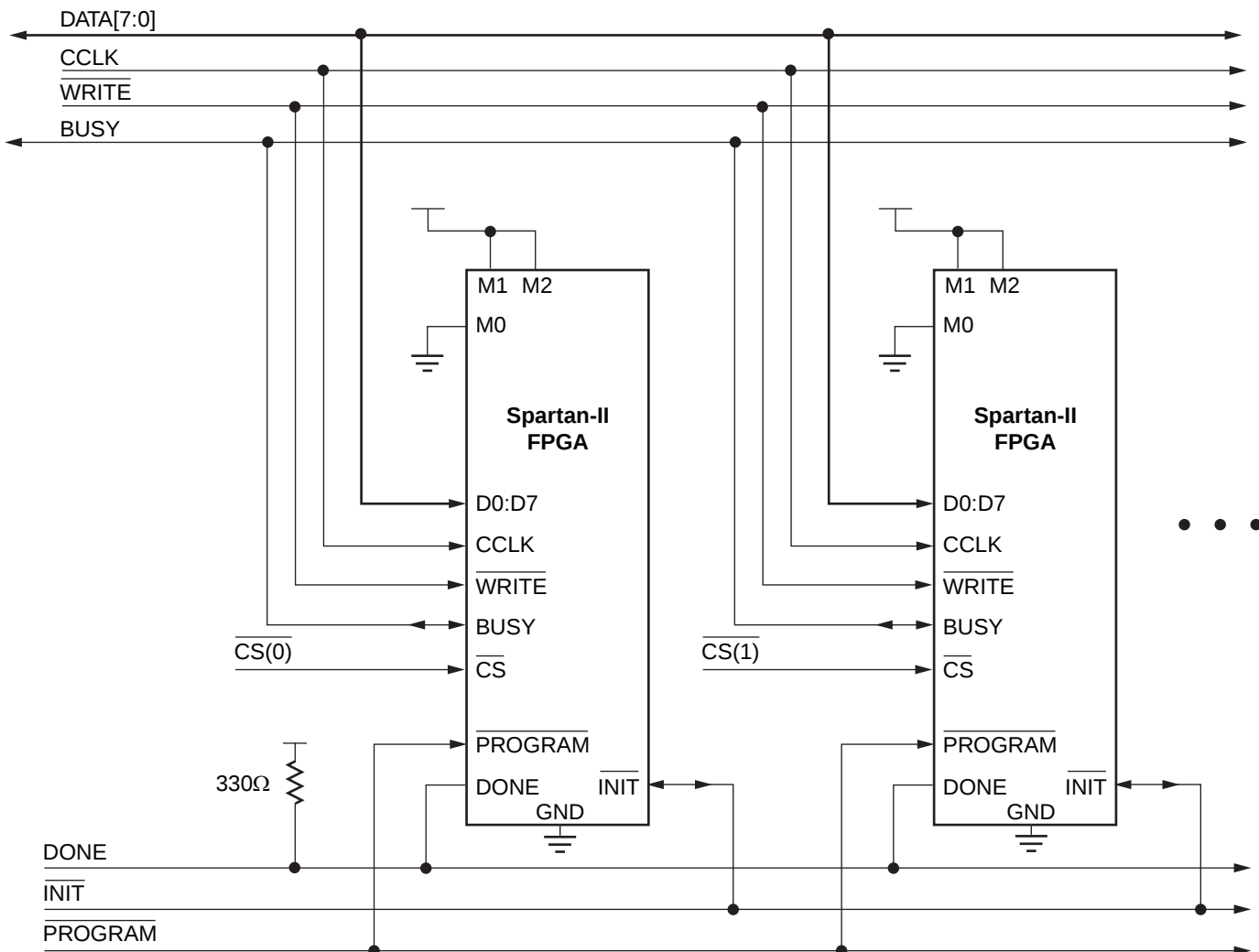
Table 7: Boundary-Scan Instructions

Boundary-Scan Command	Binary Code[4:0]	Description
EXTEST	00000	Enables boundary-scan EXTEST operation
SAMPLE	00001	Enables boundary-scan SAMPLE operation
USR1	00010	Access user-defined register 1
USR2	00011	Access user-defined register 2
CFG_OUT	00100	Access the configuration bus for Readback
CFG_IN	00101	Access the configuration bus for Configuration
INTEST	00111	Enables boundary-scan INTEST operation
USRCODE	01000	Enables shifting out USER code
IDCODE	01001	Enables shifting out of ID Code
HIZ	01010	Disables output pins while enabling the Bypass Register
JSTART	01100	Clock the start-up sequence when StartupClk is TCK
BYPASS	11111	Enables BYPASS
RESERVED	All other codes	Xilinx® reserved instructions

The public boundary-scan instructions are available prior to configuration. After configuration, the public instructions remain available together with any USERCODE instructions installed during the configuration. While the SAMPLE and BYPASS instructions are available during configuration, it is recommended that boundary-scan operations not be performed during this transitional period.

In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA, and also to read back the configuration data.

To facilitate internal scan chains, the User Register provides three outputs (Reset, Update, and Shift) that represent the corresponding states in the boundary-scan internal state machine.



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Figure 18: Slave Parallel Configuration Circuit Diagram

Multiple Spartan-II FPGAs can be configured using the Slave Parallel mode, and be made to start-up simultaneously. To configure multiple devices in this way, wire the individual CCLK, Data, $\overline{\text{WRITE}}$, and BUSY pins of all the devices in parallel. The individual devices are loaded separately by asserting the $\overline{\text{CS}}$ pin of each device in turn and writing the appropriate data. Sync-to-DONE start-up timing is used to ensure that the start-up sequence does not begin until all the FPGAs have been loaded. See "Start-up," page 19.

Write

When using the Slave Parallel Mode, write operations send packets of byte-wide configuration data into the FPGA. Figure 19, page 25 shows a flowchart of the write sequence used to load data into the Spartan-II FPGA. This is an expansion of the "Load Configuration Data Frames" block in Figure 11, page 18. The timing for write operations is shown in Figure 20, page 26.

For the present example, the user holds $\overline{\text{WRITE}}$ and $\overline{\text{CS}}$ Low throughout the sequence of write operations. Note that when $\overline{\text{CS}}$ is asserted on successive CCLKs, $\overline{\text{WRITE}}$ must remain either asserted or de-asserted. Otherwise an abort will be initiated, as in the next section.

1. Drive data onto D0:D7. Note that to avoid contention, the data source should not be enabled while $\overline{\text{CS}}$ is Low and $\overline{\text{WRITE}}$ is High. Similarly, while $\overline{\text{WRITE}}$ is High, no more than one device's $\overline{\text{CS}}$ should be asserted.
2. On the rising edge of CCLK: If BUSY is Low, the data is accepted on this clock. If BUSY is High (from a previous write), the data is not accepted. Acceptance will instead occur on the first clock after BUSY goes Low, and the data must be held until this happens.
3. Repeat steps 1 and 2 until all the data has been sent.
4. De-assert $\overline{\text{CS}}$ and $\overline{\text{WRITE}}$.

Design Considerations

This section contains more detailed design information on the following features:

- Delay-Locked Loop . . . see [page 27](#)
- Block RAM . . . see [page 32](#)
- Versatile I/O . . . see [page 36](#)

Using Delay-Locked Loops

The Spartan-II FPGA family provides up to four fully digital dedicated on-chip Delay-Locked Loop (DLL) circuits which provide zero propagation delay, low clock skew between output clock signals distributed throughout the device, and advanced clock domain control. These dedicated DLLs can be used to implement several circuits that improve and simplify system level design.

Introduction

Quality on-chip clock distribution is important. Clock skew and clock delay impact device performance and the task of managing clock skew and clock delay with conventional clock trees becomes more difficult in large devices. The Spartan-II family of devices resolve this potential problem by providing up to four fully digital dedicated on-chip Delay-Locked Loop (DLL) circuits which provide zero propagation delay and low clock skew between output clock signals distributed throughout the device.

Each DLL can drive up to two global clock routing networks within the device. The global clock distribution network minimizes clock skews due to loading differences. By monitoring a sample of the DLL output clock, the DLL can compensate for the delay on the routing network, effectively eliminating the delay from the external input port to the individual clock loads within the device.

In addition to providing zero delay with respect to a user source clock, the DLL can provide multiple phases of the source clock. The DLL can also act as a clock doubler or it can divide the user source clock by up to 16.

Clock multiplication gives the designer a number of design alternatives. For instance, a 50 MHz source clock doubled by the DLL can drive an FPGA design operating at 100 MHz. This technique can simplify board design because the clock path on the board no longer distributes such a high-speed signal. A multiplied clock also provides designers the option of time-domain-multiplexing, using one circuit twice per clock cycle, consuming less area than two copies of the same circuit.

The DLL can also act as a clock mirror. By driving the DLL output off-chip and then back in again, the DLL can be used to de-skew a board level clock between multiple devices.

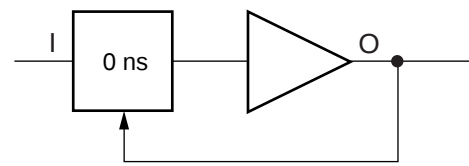
In order to guarantee the system clock establishes prior to the device "waking up," the DLL can delay the completion of

the device configuration process until after the DLL achieves lock.

By taking advantage of the DLL to remove on-chip clock delay, the designer can greatly simplify and improve system level design involving high-fanout, high-performance clocks.

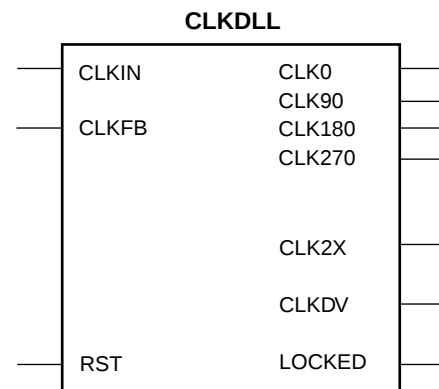
Library DLL Primitives

Figure 22 shows the simplified Xilinx library DLL macro, BUFGDLL. This macro delivers a quick and efficient way to provide a system clock with zero propagation delay throughout the device. Figure 23 and Figure 24 show the two library DLL primitives. These primitives provide access to the complete set of DLL features when implementing more complex applications.



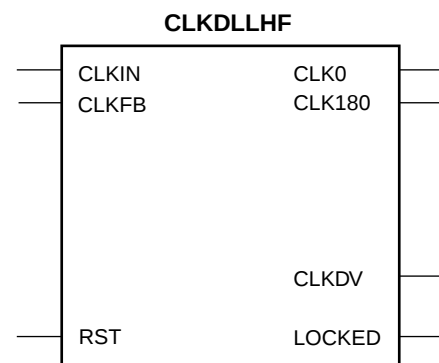
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Figure 22: Simplified DLL Macro BUFGDLL



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Figure 23: Standard DLL Primitive CLKDLL



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Figure 24: High-Frequency DLL Primitive CLKDLLHF

Using Block RAM Features

The Spartan-II FPGA family provides dedicated blocks of on-chip, true dual-read/write port synchronous RAM, with 4096 memory cells. Each port of the block RAM memory can be independently configured as a read/write port, a read port, a write port, and can be configured to a specific data width. The block RAM memory offers new capabilities allowing the FPGA designer to simplify designs.

Operating Modes

Block RAM memory supports two operating modes.

- Read Through
- Write Back

Read Through (One Clock Edge)

The read address is registered on the read port clock edge and data appears on the output after the RAM access time. Some memories may place the latch/register at the outputs depending on the desire to have a faster clock-to-out versus setup time. This is generally considered to be an inferior solution since it changes the read operation to an asynchronous function with the possibility of missing an address/control line transition during the generation of the read pulse clock.

Write Back (One Clock Edge)

The write address is registered on the write port clock edge and the data input is written to the memory and mirrored on the write port input.

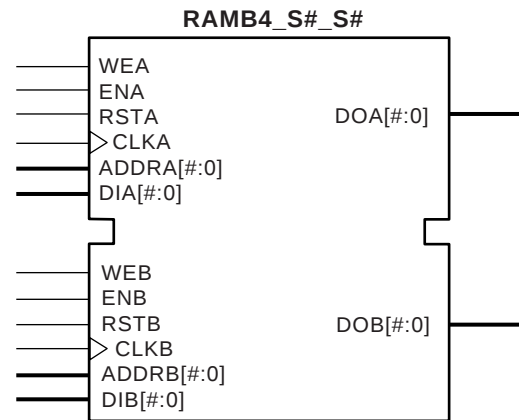
Block RAM Characteristics

1. All inputs are registered with the port clock and have a setup to clock timing specification.
2. All outputs have a read through or write back function depending on the state of the port WE pin. The outputs relative to the port clock are available after the clock-to-out timing specification.
3. The block RAM are true SRAM memories and do not have a combinatorial path from the address to the output. The LUT cells in the CLBs are still available with this function.
4. The ports are completely independent from each other (*i.e.*, clocking, control, address, read/write function, and data width) without arbitration.
5. A write operation requires only one clock edge.
6. A read operation requires only one clock edge.

The output ports are latched with a self timed circuit to guarantee a glitch free read. The state of the output port will not change until the port executes another read or write operation.

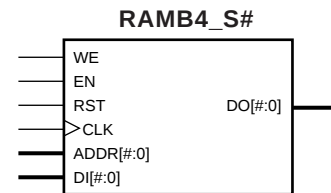
Library Primitives

Figure 31 and Figure 32 show the two generic library block RAM primitives. Table 11 describes all of the available primitives for synthesis and simulation.



DS001_31_061200

Figure 31: Dual-Port Block RAM Memory



DS001_32_061200

Figure 32: Single-Port Block RAM Memory

Table 11: Available Library Primitives

Primitive	Port A Width	Port B Width
RAMB4_S1	1	N/A
RAMB4_S1_S1		1
RAMB4_S1_S2		2
RAMB4_S1_S4		4
RAMB4_S1_S8		8
RAMB4_S1_S16		16
RAMB4_S2	2	N/A
RAMB4_S2_S2		2
RAMB4_S2_S4		4
RAMB4_S2_S8		8
RAMB4_S2_S16		16

PCI — Peripheral Component Interface

The Peripheral Component Interface (PCI) standard specifies support for both 33 MHz and 66 MHz PCI bus applications. It uses a LVTTTL input buffer and a push-pull output buffer. This standard does not require the use of a reference voltage (V_{REF}) or a board termination voltage (V_{TT}), however, it does require a 3.3V output source voltage (V_{CCO}). I/Os configured for the PCI, 33 MHz, 5V standard are also 5V-tolerant.

GTL — Gunning Transceiver Logic Terminated

The Gunning Transceiver Logic (GTL) standard is a high-speed bus standard (JESD8.3). Xilinx has implemented the terminated variation of this standard. This standard requires a differential amplifier input buffer and an open-drain output buffer.

GTL+ — Gunning Transceiver Logic Plus

The Gunning Transceiver Logic Plus (GTL+) standard is a high-speed bus standard (JESD8.3).

HSTL — High-Speed Transceiver Logic

The High-Speed Transceiver Logic (HSTL) standard is a general purpose high-speed, 1.5V bus standard (EIA/JESD 8-6). This standard has four variations or classes. Versatile I/O devices support Class I, III, and IV. This standard requires a Differential Amplifier input buffer and a Push-Pull output buffer.

SSTL3 — Stub Series Terminated Logic for 3.3V

The Stub Series Terminated Logic for 3.3V (SSTL3) standard is a general purpose 3.3V memory bus standard (JESD8-8). This standard has two classes, I and II. Versatile I/O devices support both classes for the SSTL3 standard. This standard requires a Differential Amplifier input buffer and an Push-Pull output buffer.

SSTL2 — Stub Series Terminated Logic for 2.5V

The Stub Series Terminated Logic for 2.5V (SSTL2) standard is a general purpose 2.5V memory bus standard (JESD8-9). This standard has two classes, I and II. Versatile I/O devices support both classes for the SSTL2 standard. This standard requires a Differential Amplifier input buffer and an Push-Pull output buffer.

CTT — Center Tap Terminated

The Center Tap Terminated (CTT) standard is a 3.3V memory bus standard (JESD8-4). This standard requires a Differential Amplifier input buffer and a Push-Pull output buffer.

AGP-2X — Advanced Graphics Port

The AGP standard is a 3.3V Advanced Graphics Port-2X bus standard used with processors for graphics applications. This standard requires a Push-Pull output buffer and a Differential Amplifier input buffer.

Library Primitives

The Xilinx library includes an extensive list of primitives designed to provide support for the variety of Versatile I/O features. Most of these primitives represent variations of the five generic Versatile I/O primitives:

- IBUF (input buffer)
- IBUFG (global clock input buffer)
- OBUF (output buffer)
- OBUFT (3-state output buffer)
- IOBUF (input/output buffer)

These primitives are available with various extensions to define the desired I/O standard. However, it is recommended that customers use a property or attribute on the generic primitive to specify the I/O standard. See "[Versatile I/O Properties](#)".

IBUF

Signals used as inputs to the Spartan-II device must source an input buffer (IBUF) via an external input port. The generic IBUF primitive appears in [Figure 35](#). The assumed standard is LVTTTL when the generic IBUF has no specified extension or property.

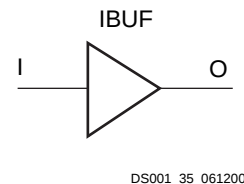


Figure 35: Input Buffer (IBUF) Primitive

When the IBUF primitive supports an I/O standard such as LVTTTL, LVCMOS, or PCI33_5, the IBUF automatically configures as a 5V tolerant input buffer unless the V_{CCO} for the bank is less than 2V. If the single-ended IBUF is placed in a bank with an HSTL standard ($V_{CCO} < 2V$), the input buffer is not 5V tolerant.

The voltage reference signal is "banked" within the Spartan-II device on a half-edge basis such that for all packages there are eight independent V_{REF} banks internally. See [Figure 36](#) for a representation of the I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a V_{REF} input.

IBUF placement restrictions require that any differential amplifier input signals within a bank be of the same standard. How to specify a specific location for the IBUF via

the LOC property is described below. Table 16 summarizes the input standards compatibility requirements.

An optional delay element is associated with each IBUF. When the IBUF drives a flip-flop within the IOB, the delay element by default activates to ensure a zero hold-time requirement. The NODELAY=TRUE property overrides this default.

When the IBUF does not drive a flip-flop within the IOB, the delay element de-activates by default to provide higher performance. To delay the input signal, activate the delay element with the DELAY=TRUE property.

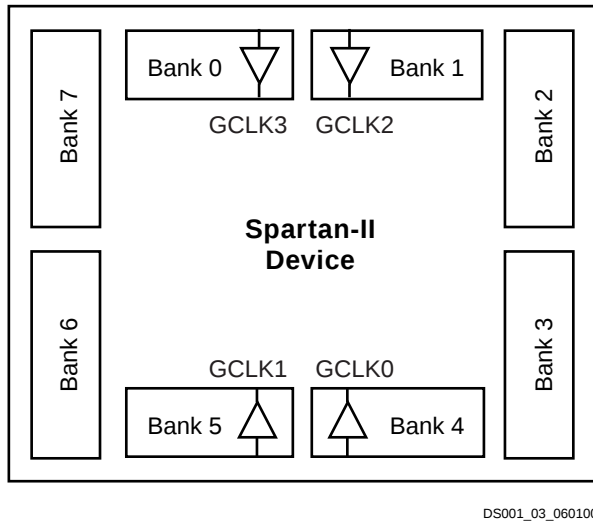


Figure 36: I/O Banks

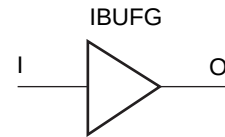
Table 16: Xilinx Input Standards Compatibility Requirements

Rule 1	All differential amplifier input signals within a bank are required to be of the same standard.
Rule 2	There are no placement restrictions for inputs with standards that require a single-ended input buffer.

IBUFG

Signals used as high fanout clock inputs to the Spartan-II device should drive a global clock input buffer (IBUFG) via an external input port in order to take advantage of one of the four dedicated global clock distribution networks. The output of the IBUFG primitive can

only drive a CLKDLL, CLKDLLHF, or a BUFG primitive. The generic IBUFG primitive appears in Figure 37.



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Figure 37: Global Clock Input Buffer (IBUFG) Primitive

With no extension or property specified for the generic IBUFG primitive, the assumed standard is LVTTTL.

The voltage reference signal is "banked" within the Spartan-II device on a half-edge basis such that for all packages there are eight independent V_{REF} banks internally. See Figure 36 for a representation of the I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a V_{REF} input.

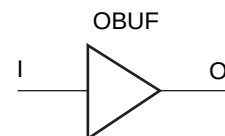
IBUFG placement restrictions require any differential amplifier input signals within a bank be of the same standard. The LOC property can specify a location for the IBUFG.

As an added convenience, the BUFGP can be used to instantiate a high fanout clock input. The BUFGP primitive represents a combination of the LVTTTL IBUFG and BUFG primitives, such that the output of the BUFGP can connect directly to the clock pins throughout the design.

The Spartan-II FPGA BUFGP primitive can only be placed in a global clock pad location. The LOC property can specify a location for the BUFGP.

OBUF

An OBUF must drive outputs through an external output port. The generic output buffer (OBUF) primitive appears in Figure 38.



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Figure 38: Output Buffer (OBUF) Primitive

With no extension or property specified for the generic OBUF primitive, the assumed standard is slew rate limited LVTTTL with 12 mA drive strength.

The LVTTTL OBUF additionally can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL output buffers have selectable drive strengths.

The format for LVTTL OBUF primitive names is as follows.

OBUF_<slew_rate>_<drive_strength>

<slew_rate> is either F (Fast), or S (Slow) and <drive_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24). The default is slew rate limited with 12 mA drive.

OBUF placement restrictions require that within a given V_{CCO} bank each OBUF share the same output source drive voltage. Input buffers of any type and output buffers that do not require V_{CCO} can be placed within any V_{CCO} bank.

Table 17 summarizes the output compatibility requirements. The LOC property can specify a location for the OBUF.

Table 17: Output Standards Compatibility Requirements

Rule 1	Only outputs with standards which share compatible V_{CCO} may be used within the same bank.
Rule 2	There are no placement restrictions for outputs with standards that do not require a V_{CCO} .
V_{CCO}	Compatible Standards
3.3	LVTTL, SSTL3_I, SSTL3_II, CTT, AGP, GTL, GTL+, PCI33_3, PCI66_3
2.5	SSTL2_I, SSTL2_II, LVCMOS2, GTL, GTL+
1.5	HSTL_I, HSTL_III, HSTL_IV, GTL, GTL+

OBUFT

The generic 3-state output buffer OBUFT, shown in Figure 39, typically implements 3-state outputs or bidirectional I/O.

With no extension or property specified for the generic OBUFT primitive, the assumed standard is slew rate limited LVTTL with 12 mA drive strength.

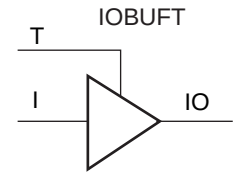
The LVTTL OBUFT can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL 3-state output buffers have selectable drive strengths.

The format for LVTTL OBUFT primitive names is as follows.

OBUFT_<slew_rate>_<drive_strength>

<slew_rate> can be either F (Fast), or S (Slow) and <drive_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24).



DS001_39_032300

Figure 39: 3-State Output Buffer Primitive (OBUFT)

The Versatile I/O OBUFT placement restrictions require that within a given V_{CCO} bank each OBUFT share the same output source drive voltage. Input buffers of any type and output buffers that do not require V_{CCO} can be placed within the same V_{CCO} bank.

The LOC property can specify a location for the OBUFT.

3-state output buffers and bidirectional buffers can have either a weak pull-up resistor, a weak pull-down resistor, or a weak "keeper" circuit. Control this feature by adding the appropriate primitive to the output net of the OBUFT (PULLUP, PULLDOWN, or KEEPER).

The weak "keeper" circuit requires the input buffer within the IOB to sample the I/O signal. So, OBUFTs programmed for an I/O standard that requires a V_{REF} have automatic placement of a V_{REF} in the bank with an OBUFT configured with a weak "keeper" circuit. This restriction does not affect most circuit design as applications using an OBUFT configured with a weak "keeper" typically implement a bidirectional I/O. In this case the IBUF (and the corresponding V_{REF}) are explicitly placed.

The LOC property can specify a location for the OBUFT.

IOBUF

Use the IOBUF primitive for bidirectional signals that require both an input buffer and a 3-state output buffer with an active high 3-state pin. The generic input/output buffer IOBUF appears in Figure 40.

With no extension or property specified for the generic IOBUF primitive, the assumed standard is LVTTL input buffer and slew rate limited LVTTL with 12 mA drive strength for the output buffer.

The LVTTL IOBUF can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL bidirectional buffers have selectable output drive strengths.

The format for LVTTL IOBUF primitive names is as follows:

SSTL2_I

A sample circuit illustrating a valid termination technique for SSTL2_I appears in Figure 49. DC voltage specifications appear in Table 27 for the SSTL2_I standard. See "DC Specifications" in Module 3 for the actual FPGA characteristics

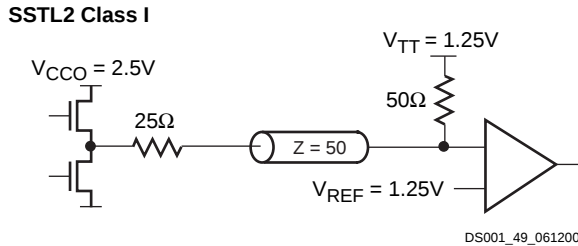


Figure 49: Terminated SSTL2 Class I

Table 27: SSTL2_I Voltage Specifications

Parameter	Min	Typ	Max
V_{CCO}	2.3	2.5	2.7
$V_{REF} = 0.5 \times V_{CCO}$	1.15	1.25	1.35
$V_{TT} = V_{REF} + N^{(1)}$	1.11	1.25	1.39
$V_{IH} \geq V_{REF} + 0.18$	1.33	1.43	3.0 ⁽²⁾
$V_{IL} \leq V_{REF} - 0.18$	-0.3 ⁽³⁾	1.07	1.17
$V_{OH} \geq V_{REF} + 0.61$	1.76	-	-
$V_{OL} \leq V_{REF} - 0.61$	-	-	0.74
I_{OH} at V_{OH} (mA)	-7.6	-	-
I_{OL} at V_{OL} (mA)	7.6	-	-

Notes:

1. N must be greater than or equal to -0.04 and less than or equal to 0.04.
2. V_{IH} maximum is $V_{CCO} + 0.3$.
3. V_{IL} minimum does not conform to the formula.

SSTL2 Class II

A sample circuit illustrating a valid termination technique for SSTL2_II appears in Figure 50. DC voltage specifications appear in Table 28 for the SSTL2_II standard. See "DC Specifications" in Module 3 for the actual FPGA characteristics.

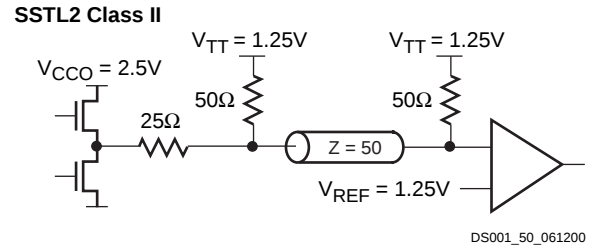


Figure 50: Terminated SSTL2 Class II

Table 28: SSTL2_II Voltage Specifications

Parameter	Min	Typ	Max
V_{CCO}	2.3	2.5	2.7
$V_{REF} = 0.5 \times V_{CCO}$	1.15	1.25	1.35
$V_{TT} = V_{REF} + N^{(1)}$	1.11	1.25	1.39
$V_{IH} \geq V_{REF} + 0.18$	1.33	1.43	3.0 ⁽²⁾
$V_{IL} \leq V_{REF} - 0.18$	-0.3 ⁽³⁾	1.07	1.17
$V_{OH} \geq V_{REF} + 0.8$	1.95	-	-
$V_{OL} \leq V_{REF} - 0.8$	-	-	0.55
I_{OH} at V_{OH} (mA)	-15.2	-	-
I_{OL} at V_{OL} (mA)	15.2	-	-

Notes:

1. N must be greater than or equal to -0.04 and less than or equal to 0.04.
2. V_{IH} maximum is $V_{CCO} + 0.3$.
3. V_{IL} minimum does not conform to the formula.

Global Clock Setup and Hold for LVTTL Standard, *with* DLL (Pin-to-Pin)

Symbol	Description	Device	Speed Grade		Units
			-6	-5	
			Min	Min	
T_{PSDLL} / T_{PHDLL}	Input setup and hold time relative to global clock input signal for LVTTL standard, no delay, IFF, ⁽¹⁾ with DLL	All	1.7 / 0	1.9 / 0	ns

Notes:

1. IFF = Input Flip-Flop or Latch
2. Setup time is measured relative to the Global Clock input signal with the fastest route and the lightest load. Hold time is measured relative to the Global Clock input signal with the slowest route and heaviest load.
3. DLL output jitter is already included in the timing calculation.
4. A zero hold time listing indicates no hold time or a negative hold time.
5. For data input with different standards, adjust the setup time delay by the values shown in ["IOB Input Delay Adjustments for Different Standards," page 57](#). For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments," page 61](#).

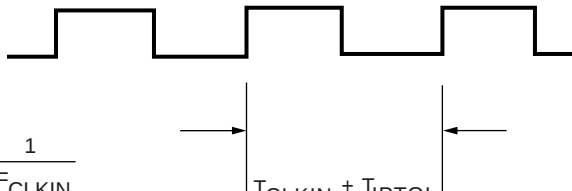
Global Clock Setup and Hold for LVTTL Standard, *without* DLL (Pin-to-Pin)

Symbol	Description	Device	Speed Grade		Units
			-6	-5	
			Min	Min	
T_{PSFD} / T_{PHFD}	Input setup and hold time relative to global clock input signal for LVTTL standard, no delay, IFF, ⁽¹⁾ without DLL	XC2S15	2.2 / 0	2.7 / 0	ns
		XC2S30	2.2 / 0	2.7 / 0	ns
		XC2S50	2.2 / 0	2.7 / 0	ns
		XC2S100	2.3 / 0	2.8 / 0	ns
		XC2S150	2.4 / 0	2.9 / 0	ns
		XC2S200	2.4 / 0	3.0 / 0	ns

Notes:

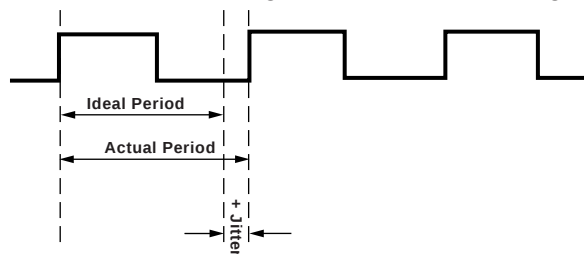
1. IFF = Input Flip-Flop or Latch
2. Setup time is measured relative to the Global Clock input signal with the fastest route and the lightest load. Hold time is measured relative to the Global Clock input signal with the slowest route and heaviest load.
3. A zero hold time listing indicates no hold time or a negative hold time.
4. For data input with different standards, adjust the setup time delay by the values shown in ["IOB Input Delay Adjustments for Different Standards," page 57](#). For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments," page 61](#).

Period Tolerance: the allowed input clock period change in nanoseconds.

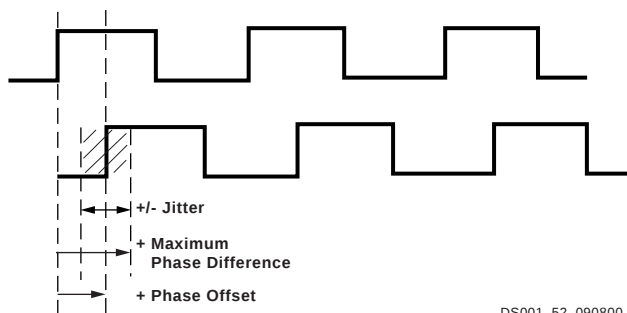
$$T_{CLKIN} = \frac{1}{F_{CLKIN}}$$


$T_{CLKIN} \pm T_{IPTOL}$

Output Jitter: the difference between an ideal reference clock edge and the actual design.



Phase Offset and Maximum Phase Difference



DS001_52_090800

Figure 52: Period Tolerance and Clock Jitter

XC2S15 Device Pinouts (Continued)

XC2S15 Pad Name		VQ100	TQ144	CS144	Bndry Scan
Function	Bank				
GND	-	-	P61	J12	-
I/O (D5)	3	P57	P60	J13	245
I/O	3	P58	P59	H10	248
I/O, V _{REF}	3	P59	P58	H11	251
I/O (D4)	3	P60	P57	H12	254
I/O	3	-	P56	H13	257
V _{CCINT}	-	P61	P55	G12	-
I/O, TRDY ⁽¹⁾	3	P62	P54	G13	260
V _{CCO}	3	P63	P53	G11	-
V _{CCO}	2	P63	P53	G11	-
GND	-	P64	P52	G10	-
I/O, IRDY ⁽¹⁾	2	P65	P51	F13	263
I/O	2	-	P50	F12	266
I/O (D3)	2	P66	P49	F11	269
I/O, V _{REF}	2	P67	P48	F10	272
I/O	2	P68	P47	E13	275
I/O (D2)	2	P69	P46	E12	278
GND	-	-	P45	E11	-
I/O (D1)	2	P70	P44	E10	281
I/O	2	P71	P43	D13	284
I/O, V _{REF}	2	P72	P41	D11	287
I/O	2	-	P40	C13	290
I/O (DIN, D0)	2	P73	P39	C12	293
I/O (DOUT, BUSY)	2	P74	P38	C11	296
CCLK	2	P75	P37	B13	299
V _{CCO}	2	P76	P36	B12	-
V _{CCO}	1	P76	P35	A13	-
TDO	2	P77	P34	A12	-
GND	-	P78	P33	B11	-
TDI	-	P79	P32	A11	-
I/O ($\overline{\text{CS}}$)	1	P80	P31	D10	0
I/O ($\overline{\text{WRITE}}$)	1	P81	P30	C10	3
I/O	1	-	P29	B10	6
I/O, V _{REF}	1	P82	P28	A10	9
I/O	1	P83	P27	D9	12
I/O	1	P84	P26	C9	15
GND	-	-	P25	B9	-
V _{CCINT}	-	P85	P24	A9	-
I/O	1	-	P23	D8	18
I/O	1	-	P22	C8	21

XC2S15 Device Pinouts (Continued)

XC2S15 Pad Name		VQ100	TQ144	CS144	Bndry Scan
Function	Bank				
I/O, V _{REF}	1	P86	P21	B8	24
I/O	1	-	P20	A8	27
I/O	1	P87	P19	B7	30
I, GCK2	1	P88	P18	A7	36
GND	-	P89	P17	C7	-
V _{CCO}	1	P90	P16	D7	-
V _{CCO}	0	P90	P16	D7	-
I, GCK3	0	P91	P15	A6	37
V _{CCINT}	-	P92	P14	B6	-
I/O	0	-	P13	C6	44
I/O, V _{REF}	0	P93	P12	D6	47
I/O	0	-	P11	A5	50
I/O	0	-	P10	B5	53
V _{CCINT}	-	P94	P9	C5	-
GND	-	-	P8	D5	-
I/O	0	P95	P7	A4	56
I/O	0	P96	P6	B4	59
I/O, V _{REF}	0	P97	P5	C4	62
I/O	0	-	P4	A3	65
I/O	0	P98	P3	B3	68
TCK	-	P99	P2	C3	-
V _{CCO}	0	P100	P1	A2	-
V _{CCO}	7	P100	P144	B2	-

04/18/01

Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. See "VCCO Banks" for details on V_{CCO} banking.

Additional XC2S15 Package Pins

VQ100

Not Connected Pins					
P28	P29	-	-	-	-

11/02/00

TQ144

Not Connected Pins					
P42	P64	P78	P101	P104	P105
P116	P138	-	-	-	-

11/02/00

CS144

Not Connected Pins					
D3	D12	J4	K13	M3	M4
M10	N3	-	-	-	-

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XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
I/O	4	-	-	-	P87	295
I/O	4	-	-	-	P88	298
I/O	4	-	P84	K8	P89	301
I/O	4	-	P83	N9	P90	304
V _{CCINT}	-	P42	P82	M9	P91	-
V _{CCO}	4	-	-	-	P92	-
GND	-	-	P81	L9	P93	-
I/O	4	P43	P80	K9	P94	307
I/O	4	P44	P79	N10	P95	310
I/O	4	-	P78	M10	P96	313
I/O, V _{REF}	4	P45	P77	L10	P98	316
I/O	4	-	-	-	P99	319
I/O	4	-	P76	N11	P100	322
I/O	4	P46	P75	M11	P101	325
I/O	4	P47	P74	L11	P102	328
GND	-	P48	P73	N12	P103	-
DONE	3	P49	P72	M12	P104	331
V _{CCO}	4	P50	P71	N13	P105	-
V _{CCO}	3	P50	P70	M13	P105	-
PROGRAM	-	P51	P69	L12	P106	334
I/O (INIT)	3	P52	P68	L13	P107	335
I/O (D7)	3	P53	P67	K10	P108	338
I/O	3	-	P66	K11	P109	341
I/O	3	-	-	-	P110	344
I/O, V _{REF}	3	P54	P65	K12	P111	347
I/O	3	-	P64	K13	P113	350
I/O	3	P55	P63	J10	P114	353
I/O (D6)	3	P56	P62	J11	P115	356
GND	-	-	P61	J12	P116	-
V _{CCO}	3	-	-	-	P117	-
I/O (D5)	3	P57	P60	J13	P119	359
I/O	3	P58	P59	H10	P120	362
I/O	3	-	-	-	P121	365
I/O	3	-	-	-	P122	368
I/O	3	-	-	-	P123	371
GND	-	-	-	-	P124	-
I/O, V _{REF}	3	P59	P58	H11	P125	374
I/O (D4)	3	P60	P57	H12	P126	377
I/O	3	-	P56	H13	P127	380
V _{CCINT}	-	P61	P55	G12	P128	-
I/O, TRDY ⁽¹⁾	3	P62	P54	G13	P129	386

XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
V _{CCO}	3	P63	P53	G11	P130	-
V _{CCO}	2	P63	P53	G11	P130	-
GND	-	P64	P52	G10	P131	-
I/O, IRDY ⁽¹⁾	2	P65	P51	F13	P132	389
I/O	2	-	-	-	P133	392
I/O	2	-	P50	F12	P134	395
I/O (D3)	2	P66	P49	F11	P135	398
I/O, V _{REF}	2	P67	P48	F10	P136	401
GND	-	-	-	-	P137	-
I/O	2	-	-	-	P138	404
I/O	2	-	-	-	P139	407
I/O	2	-	-	-	P140	410
I/O	2	P68	P47	E13	P141	413
I/O (D2)	2	P69	P46	E12	P142	416
V _{CCO}	2	-	-	-	P144	-
GND	-	-	P45	E11	P145	-
I/O (D1)	2	P70	P44	E10	P146	419
I/O	2	P71	P43	D13	P147	422
I/O	2	-	P42	D12	P148	425
I/O, V _{REF}	2	P72	P41	D11	P150	428
I/O	2	-	-	-	P151	431
I/O	2	-	P40	C13	P152	434
I/O (DIN, D0)	2	P73	P39	C12	P153	437
I/O (DOUT, BUSY)	2	P74	P38	C11	P154	440
CCLK	2	P75	P37	B13	P155	443
V _{CCO}	2	P76	P36	B12	P156	-
V _{CCO}	1	P76	P35	A13	P156	-
TDO	2	P77	P34	A12	P157	-
GND	-	P78	P33	B11	P158	-
TDI	-	P79	P32	A11	P159	-
I/O (CS)	1	P80	P31	D10	P160	0
I/O (WRITE)	1	P81	P30	C10	P161	3
I/O	1	-	P29	B10	P162	6
I/O	1	-	-	-	P163	9
I/O, V _{REF}	1	P82	P28	A10	P164	12
I/O	1	-	-	-	P166	15
I/O	1	P83	P27	D9	P167	18
I/O	1	P84	P26	C9	P168	21
GND	-	-	P25	B9	P169	-
V _{CCO}	1	-	-	-	P170	-

XC2S50 Device Pinouts

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
GND	-	P143	P1	GND*	-
TMS	-	P142	P2	D3	-
I/O	7	P141	P3	C2	149
I/O	7	-	-	A2	152
I/O	7	P140	P4	B1	155
I/O	7	-	-	E3	158
I/O	7	-	P5	D2	161
GND	-	-	-	GND*	-
I/O, V _{REF}	7	P139	P6	C1	164
I/O	7	-	P7	F3	167
I/O	7	-	-	E2	170
I/O	7	P138	P8	E4	173
I/O	7	P137	P9	D1	176
I/O	7	P136	P10	E1	179
GND	-	P135	P11	GND*	-
V _{CCO}	7	-	P12	V _{CCO} Bank 7*	-
V _{CCINT}	-	-	P13	V _{CCINT} *	-
I/O	7	P134	P14	F2	182
I/O	7	P133	P15	G3	185
I/O	7	-	-	F1	188
I/O	7	-	P16	F4	191
I/O	7	-	P17	F5	194
I/O	7	-	P18	G2	197
GND	-	-	P19	GND*	-
I/O, V _{REF}	7	P132	P20	H3	200
I/O	7	P131	P21	G4	203
I/O	7	-	-	H2	206
I/O	7	P130	P22	G5	209
I/O	7	-	P23	H4	212
I/O, IRDY ⁽¹⁾	7	P129	P24	G1	215
GND	-	P128	P25	GND*	-
V _{CCO}	7	P127	P26	V _{CCO} Bank 7*	-
V _{CCO}	6	P127	P26	V _{CCO} Bank 6*	-
I/O, TRDY ⁽¹⁾	6	P126	P27	J2	218
V _{CCINT}	-	P125	P28	V _{CCINT} *	-
I/O	6	P124	P29	H1	224
I/O	6	-	-	J4	227
I/O	6	P123	P30	J1	230
I/O, V _{REF}	6	P122	P31	J3	233

XC2S50 Device Pinouts (Continued)

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
GND	-	-	P32	GND*	-
I/O	6	-	P33	K5	236
I/O	6	-	P34	K2	239
I/O	6	-	P35	K1	242
I/O	6	-	-	K3	245
I/O	6	P121	P36	L1	248
I/O	6	P120	P37	L2	251
V _{CCINT}	-	-	P38	V _{CCINT} *	-
V _{CCO}	6	-	P39	V _{CCO} Bank 6*	-
GND	-	P119	P40	GND*	-
I/O	6	P118	P41	K4	254
I/O	6	P117	P42	M1	257
I/O	6	P116	P43	L4	260
I/O	6	-	-	M2	263
I/O	6	-	P44	L3	266
I/O, V _{REF}	6	P115	P45	N1	269
GND	-	-	-	GND*	-
I/O	6	-	P46	P1	272
I/O	6	-	-	L5	275
I/O	6	P114	P47	N2	278
I/O	6	-	-	M4	281
I/O	6	P113	P48	R1	284
I/O	6	P112	P49	M3	287
M1	-	P111	P50	P2	290
GND	-	P110	P51	GND*	-
M0	-	P109	P52	N3	291
V _{CCO}	6	P108	P53	V _{CCO} Bank 6*	-
V _{CCO}	5	P107	P53	V _{CCO} Bank 5*	-
M2	-	P106	P54	R3	292
I/O	5	-	-	N5	299
I/O	5	P103	P57	T2	302
I/O	5	-	-	P5	305
I/O	5	-	P58	T3	308
GND	-	-	-	GND*	-
I/O, V _{REF}	5	P102	P59	T4	311
I/O	5	-	P60	M6	314
I/O	5	-	-	T5	317
I/O	5	P101	P61	N6	320
I/O	5	P100	P62	R5	323

Additional XC2S50 Package Pins (Continued)

PQ208

Not Connected Pins					
P55	P56	-	-	-	-

11/02/00

FG256

V _{CCINT} Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V _{CCO} Bank 0 Pins					
E8	F8	-	-	-	-
V _{CCO} Bank 1 Pins					
E9	F9	-	-	-	-
V _{CCO} Bank 2 Pins					
H11	H12	-	-	-	-
V _{CCO} Bank 3 Pins					
J11	J12	-	-	-	-
V _{CCO} Bank 4 Pins					
L9	M9	-	-	-	-
V _{CCO} Bank 5 Pins					
L8	M8	-	-	-	-
V _{CCO} Bank 6 Pins					
J5	J6	-	-	-	-
V _{CCO} Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-

11/02/00

XC2S100 Device Pinouts

XC2S100 Pad Name						
Function	Bank	TQ144	PQ208	FG256	FG456	Bndry Scan
GND	-	P143	P1	GND*	GND*	-
TMS	-	P142	P2	D3	D3	-
I/O	7	P141	P3	C2	B1	185
I/O	7	-	-	A2	F5	191
I/O	7	P140	P4	B1	D2	194
I/O	7	-	-	-	E3	197
I/O	7	-	-	E3	G5	200
I/O	7	-	P5	D2	F3	203
GND	-	-	-	GND*	GND*	-
V _{CCO}	7	-	-	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-
I/O, V _{REF}	7	P139	P6	C1	E2	206

XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name						
Function	Bank	TQ144	PQ208	FG256	FG456	Bndry Scan
I/O	7	-	P7	F3	E1	209
I/O	7	-	-	E2	H5	215
I/O	7	P138	P8	E4	F2	218
I/O	7	-	-	-	F1	221
I/O, V _{REF}	7	P137	P9	D1	H4	224
I/O	7	P136	P10	E1	G1	227
GND	-	P135	P11	GND*	GND*	-
V _{CCO}	7	-	P12	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-
V _{CCINT}	-	-	P13	V _{CCINT} *	V _{CCINT} *	-
I/O	7	P134	P14	F2	H3	230
I/O	7	P133	P15	G3	H2	233
I/O	7	-	-	F1	J5	236
I/O	7	-	P16	F4	J2	239
I/O	7	-	P17	F5	K5	245
I/O	7	-	P18	G2	K1	248
GND	-	-	P19	GND*	GND*	-
I/O, V _{REF}	7	P132	P20	H3	K3	251
I/O	7	P131	P21	G4	K4	254
I/O	7	-	-	H2	L6	257
I/O	7	P130	P22	G5	L1	260
I/O	7	-	P23	H4	L4	266
I/O, IRDY ⁽¹⁾	7	P129	P24	G1	L3	269
GND	-	P128	P25	GND*	GND*	-
V _{CCO}	7	P127	P26	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-
V _{CCO}	6	P127	P26	V _{CCO} Bank 6*	V _{CCO} Bank 6*	-
I/O, TRDY ⁽¹⁾	6	P126	P27	J2	M1	272
V _{CCINT}	-	P125	P28	V _{CCINT} *	V _{CCINT} *	-
I/O	6	P124	P29	H1	M3	281
I/O	6	-	-	J4	M4	284
I/O	6	P123	P30	J1	M5	287
I/O, V _{REF}	6	P122	P31	J3	N2	290
GND	-	-	P32	GND*	GND*	-
I/O	6	-	P33	K5	N3	293
I/O	6	-	P34	K2	N4	296
I/O	6	-	P35	K1	P2	302
I/O	6	-	-	K3	P4	305
I/O	6	P121	P36	L1	P3	308
I/O	6	P120	P37	L2	R2	311

XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name						
Function	Bank	TQ144	PQ208	FG256	FG456	Bndry Scan
I/O	0	-	P188	A6	C10	107
I/O, V _{REF}	0	P12	P189	B7	A9	110
GND	-	-	P190	GND*	GND*	-
I/O	0	-	P191	C8	B9	113
I/O	0	-	P192	D7	E10	116
I/O	0	-	P193	E7	A8	122
I/O	0	-	-	-	D9	125
I/O	0	P11	P194	C7	E9	128
I/O	0	P10	P195	B6	A7	131
V _{CCINT}	-	P9	P196	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	0	-	P197	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
GND	-	P8	P198	GND*	GND*	-
I/O	0	P7	P199	A5	B7	134
I/O, V _{REF}	0	P6	P200	C6	E8	137
I/O	0	-	-	-	D8	140
I/O	0	-	P201	B5	C7	143
I/O	0	-	-	D6	D7	146
I/O	0	-	P202	A4	D6	152
I/O, V _{REF}	0	P5	P203	B4	C6	155
V _{CCO}	0	-	-	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
GND	-	-	-	GND*	GND*	-
I/O	0	-	P204	E6	B5	158
I/O	0	-	-	D5	E7	161
I/O	0	-	-	-	E6	164
I/O	0	P4	P205	A3	B4	167
I/O	0	-	-	C5	A3	170
I/O	0	P3	P206	B3	C5	176
TCK	-	P2	P207	C4	C4	-
V _{CCO}	0	P1	P208	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
V _{CCO}	7	P144	P208	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-

04/18/01

Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. Pads labelled GND*, V_{CCINT}*, V_{CCO} Bank 0*, V_{CCO} Bank 1*, V_{CCO} Bank 2*, V_{CCO} Bank 3*, V_{CCO} Bank 4*, V_{CCO} Bank 5*, V_{CCO} Bank 6*, V_{CCO} Bank 7* are internally bonded to independent ground or power planes within the package.
3. See "VCCO Banks" for details on V_{CCO} banking.

Additional XC2S100 Package Pins

TQ144

Not Connected Pins					
P104	P105	-	-	-	-

11/02/00

PQ208

Not Connected Pins					
P55	P56	-	-	-	-

11/02/00

FG256

V _{CCINT} Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V _{CCO} Bank 0 Pins					
E8	F8	-	-	-	-
V _{CCO} Bank 1 Pins					
E9	F9	-	-	-	-
V _{CCO} Bank 2 Pins					
H11	H12	-	-	-	-
V _{CCO} Bank 3 Pins					
J11	J12	-	-	-	-
V _{CCO} Bank 4 Pins					
L9	M9	-	-	-	-
V _{CCO} Bank 5 Pins					
L8	M8	-	-	-	-
V _{CCO} Bank 6 Pins					
J5	J6	-	-	-	-
V _{CCO} Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-

11/02/00

FG456

V _{CCINT} Pins					
E5	E18	F6	F17	G7	G8
G9	G14	G15	G16	H7	H16
J7	J16	P7	P16	R7	R16
T7	T8	T9	T14	T15	T16
U6	U17	V5	V18	-	-
V _{CCO} Bank 0 Pins					

Additional XC2S100 Package Pins (Continued)

F10	F7	F8	F9	G10	G11
V _{CCO} Bank 1 Pins					
F13	F14	F15	F16	G12	G13
V _{CCO} Bank 2 Pins					
G17	H17	J17	K16	K17	L16
V _{CCO} Bank 3 Pins					
M16	N16	N17	P17	R17	T17
V _{CCO} Bank 4 Pins					
T12	T13	U13	U14	U15	U16
V _{CCO} Bank 5 Pins					
T10	T11	U10	U7	U8	U9
V _{CCO} Bank 6 Pins					
M7	N6	N7	P6	R6	T6
V _{CCO} Bank 7 Pins					
G6	H6	J6	K6	K7	L7
GND Pins					
A1	A22	B2	B21	C3	C20
J9	J10	J11	J12	J13	J14
K9	K10	K11	K12	K13	K14
L9	L10	L11	L12	L13	L14
M9	M10	M11	M12	M13	M14
N9	N10	N11	N12	N13	N14
P9	P10	P11	P12	P13	P14
Y3	Y20	AA2	AA21	AB1	AB22
Not Connected Pins					
A2	A4	A5	A6	A12	A13
A14	A15	A17	B3	B6	B8
B11	B14	B16	B19	C1	C2
C8	C9	C12	C18	C22	D1
D4	D5	D10	D18	D19	D21
E4	E11	E13	E15	E16	E17
E19	E22	F4	F11	F22	G2
G3	G4	G19	G22	H1	H21
J1	J3	J4	J19	J20	K2
K18	K19	L2	L5	L18	L19
M2	M6	M17	M18	M21	N1
N5	N19	P1	P5	P19	P22
R1	R3	R20	R22	T5	T19
U3	U11	U18	V1	V2	V10
V12	V17	V3	V4	V6	V8
V20	V21	V22	W4	W5	W9
W13	W14	W15	W16	W19	Y5
Y14	Y18	Y22	AA1	AA3	AA6
AA9	AA10	AA11	AA16	AA17	AA18
AA22	AB3	AB4	AB7	AB8	AB12
AB14	AB21	-	-	-	-

11/02/00

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	4	P90	R11	AA15	595
V _{CCINT}	-	P91	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	4	P92	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	P93	GND*	GND*	-
I/O	4	P94	M11	Y15	598
I/O, V _{REF}	4	P95	T11	AB16	601
I/O	4	-	-	AB17	604
I/O	4	P96	N11	V15	607
I/O	4	-	R12	Y16	610
I/O	4	-	-	AA17	613
I/O	4	-	-	W16	616
I/O	4	P97	P11	AB18	619
I/O, V _{REF}	4	P98	T12	AB19	622
V _{CCO}	4	-	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	-	GND*	GND*	-
I/O	4	P99	T13	Y17	625
I/O	4	-	N12	V16	628
I/O	4	-	-	AA18	631
I/O	4	-	-	W17	634
I/O	4	P100	R13	AB20	637
GND	-	-	GND*	GND*	-
I/O	4	-	P12	AA19	640
I/O	4	-	-	V17	643
I/O	4	-	-	Y18	646
I/O	4	P101	P13	AA20	649
I/O	4	P102	T14	W18	652
GND	-	P103	GND*	GND*	-
DONE	3	P104	R14	Y19	655
V _{CCO}	4	P105	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
V _{CCO}	3	P105	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
PROGRAM	-	P106	P15	W20	658
I/O (INIT)	3	P107	N15	V19	659
I/O (D7)	3	P108	N14	Y21	662
I/O	3	-	-	V20	665
I/O	3	-	-	AA22	668
I/O	3	-	T15	W21	671
GND	-	-	GND*	GND*	-
I/O	3	P109	M13	U20	674

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	3	-	-	U19	677
I/O	3	-	-	V21	680
I/O	3	-	R16	T18	683
I/O	3	P110	M14	W22	686
GND	-	-	GND*	GND*	-
V _{CCO}	3	-	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
I/O, V _{REF}	3	P111	L14	U21	689
I/O	3	P112	M15	T20	692
I/O	3	-	-	T19	695
I/O	3	-	-	V22	698
I/O	3	-	L12	T21	701
I/O	3	P113	P16	R18	704
I/O	3	-	-	U22	707
I/O, V _{REF}	3	P114	L13	R19	710
I/O (D6)	3	P115	N16	T22	713
GND	-	P116	GND*	GND*	-
V _{CCO}	3	P117	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
V _{CCINT}	-	P118	V _{CCINT} *	V _{CCINT} *	-
I/O (D5)	3	P119	M16	R21	716
I/O	3	P120	K14	P18	719
I/O	3	-	-	P19	725
I/O	3	-	L16	P20	728
I/O	3	P121	K13	P21	731
I/O	3	-	-	N19	734
I/O	3	P122	L15	N18	740
I/O	3	P123	K12	N20	743
GND	-	P124	GND*	GND*	-
V _{CCO}	3	-	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
I/O, V _{REF}	3	P125	K16	N21	746
I/O (D4)	3	P126	J16	N22	749
I/O	3	-	J14	M19	752
I/O	3	P127	K15	M20	755
I/O	3	-	-	M18	758
V _{CCINT}	-	P128	V _{CCINT} *	V _{CCINT} *	-
I/O, TRDY ⁽¹⁾	3	P129	J15	M22	764
V _{CCO}	3	P130	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
V _{CCO}	2	P130	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P131	GND*	GND*	-

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O, IRDY ⁽¹⁾	2	P132	H16	L20	767
I/O	2	P133	H14	L17	770
I/O	2	-	-	L18	773
I/O	2	P134	H15	L21	776
I/O	2	-	J13	L22	779
I/O (D3)	2	P135	G16	K20	782
I/O, V _{REF}	2	P136	H13	K21	785
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P137	GND*	GND*	-
I/O	2	P138	G14	K22	788
I/O	2	P139	G15	J21	791
I/O	2	-	-	J20	797
I/O	2	P140	G12	J18	800
I/O	2	-	F16	J22	803
I/O	2	-	-	J19	806
I/O	2	P141	G13	H19	812
I/O (D2)	2	P142	F15	H20	815
V _{CCINT}	-	P143	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	2	P144	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P145	GND*	GND*	-
I/O (D1)	2	P146	E16	H22	818
I/O, V _{REF}	2	P147	F14	H18	821
I/O	2	-	-	G21	824
I/O	2	P148	D16	G18	827
I/O	2	-	F12	G20	830
I/O	2	-	-	G19	833
I/O	2	-	-	F22	836
I/O	2	P149	E15	F19	839
I/O, V _{REF}	2	P150	F13	F21	842
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	-	GND*	GND*	-
I/O	2	P151	E14	F20	845
I/O	2	-	C16	F18	848
I/O	2	-	-	E22	851
I/O	2	-	-	E21	854
I/O	2	P152	E13	D22	857
GND	-	-	GND*	GND*	-
I/O	2	-	B16	E20	860
I/O	2	-	-	D21	863

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	2	-	-	C22	866
I/O (DIN, D0)	2	P153	D14	D20	869
I/O (DOUT, BUSY)	2	P154	C15	C21	872
CCLK	2	P155	D15	B22	875
V _{CCO}	2	P156	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
V _{CCO}	1	P156	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
TDO	2	P157	B14	A21	-
GND	-	P158	GND*	GND*	-
TDI	-	P159	A15	B20	-
I/O ($\overline{\text{CS}}$)	1	P160	B13	C19	0
I/O ($\overline{\text{WRITE}}$)	1	P161	C13	A20	3
I/O	1	-	-	B19	6
I/O	1	-	-	C18	9
I/O	1	-	C12	D17	12
GND	-	-	GND*	GND*	-
I/O	1	P162	A14	A19	15
I/O	1	-	-	B18	18
I/O	1	-	-	E16	21
I/O	1	-	D12	C17	24
I/O	1	P163	B12	D16	27
GND	-	-	GND*	GND*	-
V _{CCO}	1	-	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
I/O, V _{REF}	1	P164	C11	A18	30
I/O	1	P165	A13	B17	33
I/O	1	-	-	E15	36
I/O	1	-	-	A17	39
I/O	1	-	D11	D15	42
I/O	1	P166	A12	C16	45
I/O	1	-	-	D14	48
I/O, V _{REF}	1	P167	E11	E14	51
I/O	1	P168	B11	A16	54
GND	-	P169	GND*	GND*	-
V _{CCO}	1	P170	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
V _{CCINT}	-	P171	V _{CCINT} *	V _{CCINT} *	-
I/O	1	P172	A11	C15	57
I/O	1	P173	C10	B15	60
I/O	1	-	-	A15	66
I/O	1	-	-	F12	69

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	1	P174	B10	C14	72
I/O	1	-	-	B14	75
I/O	1	P175	D10	D13	81
I/O	1	P176	A10	C13	84
GND	-	P177	GND*	GND*	-
V _{CCO}	1	-	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
I/O, V _{REF}	1	P178	B9	B13	87
I/O	1	P179	E10	E12	90
I/O	1	-	A9	B12	93
I/O	1	P180	D9	D12	96
I/O	1	-	-	C12	99
I/O	1	P181	A8	D11	102
I, GCK2	1	P182	C9	A11	108
GND	-	P183	GND*	GND*	-
V _{CCO}	1	P184	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
V _{CCO}	0	P184	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
I, GCK3	0	P185	B8	C11	109
V _{CCINT}	-	P186	V _{CCINT} *	V _{CCINT} *	-
I/O	0	-	-	E11	116
I/O	0	P187	A7	A10	119
I/O	0	-	D8	B10	122
I/O	0	P188	A6	C10	125
I/O, V _{REF}	0	P189	B7	A9	128
V _{CCO}	0	-	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
GND	-	P190	GND*	GND*	-
I/O	0	P191	C8	B9	131
I/O	0	P192	D7	E10	134
I/O	0	-	-	D10	140
I/O	0	P193	E7	A8	143
I/O	0	-	-	D9	146
I/O	0	-	-	B8	149
I/O	0	P194	C7	E9	155
I/O	0	P195	B6	A7	158

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
V _{CCINT}	-	P196	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	0	P197	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
GND	-	P198	GND*	GND*	-
I/O	0	P199	A5	B7	161
I/O, V _{REF}	0	P200	C6	E8	164
I/O	0	-	-	D8	167
I/O	0	P201	B5	C7	170
I/O	0	-	D6	D7	173
I/O	0	-	-	B6	176
I/O	0	-	-	A5	179
I/O	0	P202	A4	D6	182
I/O, V _{REF}	0	P203	B4	C6	185
V _{CCO}	0	-	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
GND	-	-	GND*	GND*	-
I/O	0	P204	E6	B5	188
I/O	0	-	D5	E7	191
I/O	0	-	-	A4	194
I/O	0	-	-	E6	197
I/O	0	P205	A3	B4	200
GND	-	-	GND*	GND*	-
I/O	0	-	C5	A3	203
I/O	0	-	-	B3	206
I/O	0	-	-	D5	209
I/O	0	P206	B3	C5	212
TCK	-	P207	C4	C4	-
V _{CCO}	0	P208	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
V _{CCO}	7	P208	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-

04/18/01

Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. Pads labelled GND*, V_{CCINT}*, V_{CCO} Bank 0*, V_{CCO} Bank 1*, V_{CCO} Bank 2*, V_{CCO} Bank 3*, V_{CCO} Bank 4*, V_{CCO} Bank 5*, V_{CCO} Bank 6*, V_{CCO} Bank 7* are internally bonded to independent ground or power planes within the package.
3. See "VCCO Banks" for details on V_{CCO} banking.